Special Issue

Quality Inspection and Control Technology for Advanced Equipment and Machining Processes

Message from the Guest Editors

The quality inspection and control of advanced equipment and processing processes has become a multidisciplinary frontier, attracting the interest of many researchers from different fields. However, there are still many challenges to overcome. This Special Issue of Applied Sciences on "Quality Inspection and Control Technology for Advanced Equipment and Machining Processes" aims to give an overview of the latest developments regarding quality inspection and control technologies for advanced equipment and machining processes. Topics of discussion include, but are not limited to, the exploration of new theories, methods, technologies, processes, applications, etc., which enable breakthroughs in many valuable research areas such as machining error measurement and compensation, active and adaptive control of machining accuracy, advanced equipment assembly quality control technology, etc.

Guest Editors

Prof. Dr. Jun Yang

Prof. Dr. Jixiang Yang

Dr. Lintao Wang

Deadline for manuscript submissions

closed (20 June 2024)



Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



mdpi.com/si/177426

Applied Sciences Editorial Office MDPI, Grosspeteranlage 5 4052 Basel, Switzerland Tel: +41 61 683 77 34 applsci@mdpi.com

mdpi.com/journal/applsci





Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

